

TAKAHASHI LAB.

[Nano-probing Technologies]

Department of Informatics and Electronics

<http://www.spm.iis.u-tokyo.ac.jp>

Nano-electronics

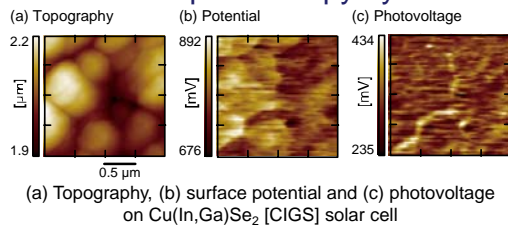
Department of Electrical Engineering and Information Systems

Development of novel nano-probing technologies and nano-scale characterization of nano-materials for future device application

We aim at investigating electronic and optical properties in various nano-materials by means of nano-probe methods such as scanning tunneling microscopy (STM), atomic force microscopy (AFM) and related ones.

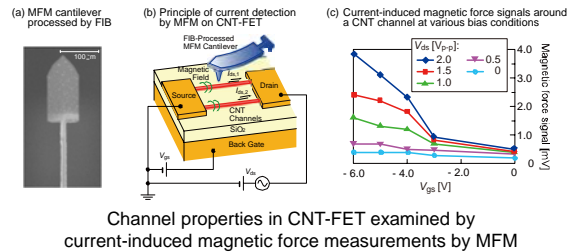
◆ Characterization of Solar Cell Materials

- Photovoltaic properties and minority carrier dynamics
- Photothermal spectroscopy by AFM



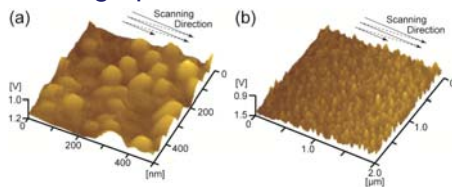
◆ Characterization of Carbon Nanotube FETs

- Current detection by magnetic force microscopy (MFM)



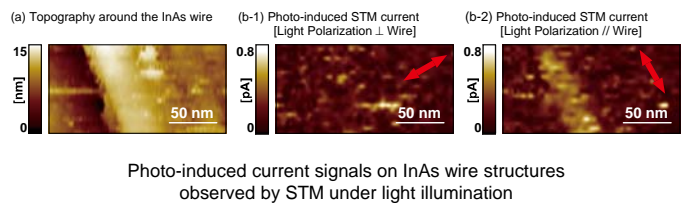
◆ Development of Novel SPM Methods

- Fast imaging in AFM
- Novel operation methods for high performance SPMs



◆ Physics in Quantum Nanostructure

- Observation of physical phenomena in low-dimensional semiconductors



Multi-functional SPM equipments: (a) air type, (b)/(c) high vacuum and variable temperature type



Tunable Ti:Al₂O₃ laser with solid state green laser



Variable temperature SPM in ultra-high vacuum